

STROM ET AL. – 10/799,575  
Attorney Docket: 044182-0308721

### REMARKS

Applicants respectfully request reconsideration and allowance in view of the following remarks. In the Office Action, claims 1-4 and 7 stand rejected under 35 U.S.C. 102(e) as being anticipated by U.S. Patent 6,710,798 to Hershel et al. ("Hershel"). The Office Action objects to claims 5 and 6 as being dependent on a rejected base claim.

#### *Allowable Subject Matter*

Applicants thank the Examiner for acknowledging the allowable subject matter in the present Application. However, Applicants believe that claims 1-4 are also allowable and, pending further review by the Examiner, Applicants respectfully decline to amend the claims to independent form at this time.

#### *Rejections under 35 U.S.C. §102(e)*

The claims of the present Application each require computing planarity effects due to fiducial plate deflection and combining planarity effects due to probe card deflection and due to probe card fixture deflection. Hershel does not teach explicitly or impliedly measurement or combination of effects due to fiducial plate, probe card or probe card fixture deflection. Hershel teaches the determination of the position geometric centroids of a probe tip with respect to an index mark on a fiduciary plate (see, e.g., Hershel Abstract). Hershel teaches deflection in the context of over travel that causes *probe pin deflection* from rest positions when the probe pins are brought into contact with a metalized pad (Hershel, col. 1, lines 26-49).

Hershel does not teach the deflection of a probe card under the load of a plurality of pins as taught in the present Application:

In a typical probe card analyzer system taking electrical planarity measurements across a single large contact surface, the *deflection of the probe card, the probe card fixture, the metrology frame, or some combination thereof, may become an integral part of the planarity measurement itself*. This is due to the fact that the loads arising from contact with lower probes cause deflection, which in turn increases the apparent planarity of higher probes.

(Present Application at para. [0005], with emphasis added). Thus, in contrast to Hershel, the present Application is directed to, *inter alia*, providing a system and method of mitigating the effects of component deflections in a probe card analyzer system, including fiducial plate, probe card and probe card fixture deflection (Present Application at paras. [0008-0009]).

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Therefore, Hershel cannot be said to teach each and every element of the claims because Hershel does not teach or suggest the deflection of fiducial plate, probe card and probe card fixture deflection components in a probe card analyzer system. Consequently, Hershel cannot be said to teach – explicitly or impliedly – computing planarity effects due to fiducial plate deflection and combining planarity effects due to probe card deflection and due to probe card fixture deflection as required by independent claim 1. For at least these reasons, the rejections of the claims should be withdrawn.

#### CONCLUSION

All objections and rejections having been addressed, and in view of the foregoing, the claims are believed to be in form for allowance, and such action is earnestly solicited. The Examiner is kindly requested to contact the undersigned at the telephone number listed below if any points remain in issue which may be best resolved through a personal or telephone interview. Please charge any fees associated with the submission of this paper to Deposit Account Number 033975. The Commissioner for Patents is also authorized to credit any over payments to the above-referenced Deposit Account.

Respectfully submitted,

PILLSBURY WINTHROP SHAW PITTMAN LLP



Anthony G. Smyth  
Reg. No. 55,636  
Tel. No. 858 509.4007  
Fax No.

Date: May 23, 2006  
11682 El Camino Real  
Suite 200  
San Diego, CA 92130-2092  
(619) 234-5000